# Am9114/Am91L14

1024x4 Static RAM



#### **DISTINCTIVE CHARACTERISTICS**

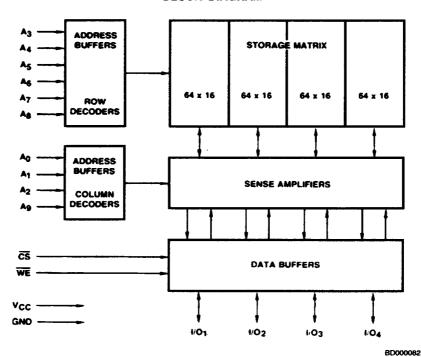
- Low operating and standby power
- Access times down to 200 ns
- Am9114 is a direct plug-in replacement for 2114
- High output drive: 3.2-mA sink current @ 0.4 V
- TTL-identical input/output levels

#### **GENERAL DESCRIPTION**

The Am9114/Am91L14 Series are high-performance, static, N-Channel, read/write, random-access memories organized as 1024 x 4. Operation is from a single 5-V supply, and all input/output levels are identical to standard TTL specifications. Low-power version is available with power savings of over 30%.

Data readout is not destructive and the same polarity as data input. CS provides for easy selection of an individual package when the outputs are OR-tied. The outputs of 3.2 mA for Am9114 provides increased short-circuit current for improved capacitive drive.

#### **BLOCK DIAGRAM**



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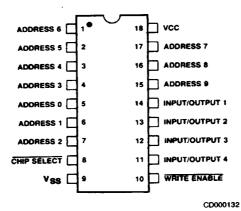
#### PRODUCT SELECTOR GUIDE

Part Number			Am9114	Am9114/91L1		
Speed Indicator  Maximum Access Time (ns)		В		C	E	
			450	300	200	
0 to +70°C	T	Standard	70	70	70	
	ICC (mA)	Low-Power	50	50	50	
-55 to +125°C		Standard	80	80	80	
	ICC (mA)	Low-Power	60	60	60	

#### **CONNECTION DIAGRAM**

**Top View** 

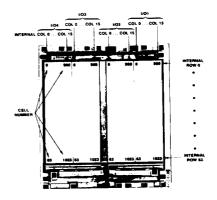
DIPs



Note: Pin 1 is marked for orientation.

#### METALLIZATION AND PAD LAYOUT

Address Designators		
External	Internal	
A <sub>0</sub>	Ag	
A <sub>1</sub>	A <sub>8</sub>	
A <sub>2</sub>	A <sub>7</sub>	
A <sub>3</sub>	Ao	
A4	A <sub>1</sub>	
A <sub>5</sub>	A <sub>2</sub>	
A <sub>6</sub>	А3	
A <sub>7</sub>	A <sub>4</sub>	
A <sub>8</sub>	A <sub>5</sub>	
Ag	A <sub>6</sub>	



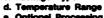
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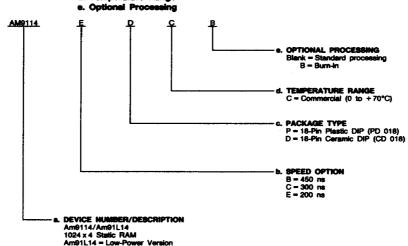
#### **ORDERING INFORMATION**

#### Standard Products

AMD standard products are available in several packages and operating ranges. The order number (Valid Combination) is formed by a combination of: a. Device Number







Valid Combinations							
AM9114B							
AM91L14B							
AM9114C	PC. PCB.						
AM91L14C	PC, PCB, DC, DCB						
AM9114E							
AM91L14E							

#### **Valid Combinations**

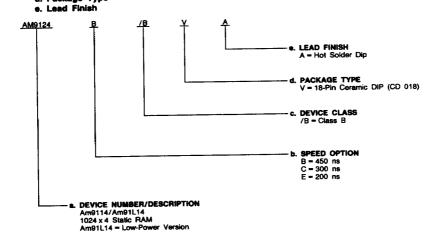
Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

### MILITARY ORDERING INFORMATION

#### **APL Products**

AMD products for Aerospace and Defense applications are available in several packages and operating ranges. APL (Approved Products List) products are fully compliant with MIL-STD-883C requirements. The order number (Valid Combination) is formed by a combination of: a. Device Number

- b. Speed Option (if applicable)
- c. Device Class
- d. Package Type



Valid Combinations				
AM9114B				
AM91L14B				
AM9114C	/BVA			
AM91L14C	/BVA			
AM9114E				
AM91L14E				

#### **Valid Combinations**

Valid Combinations list configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations or to check for newly released valid combinations.

#### **Group A Tests**

Group A tests consist of Subgroups 1, 2, 3, 7, 8, 9, 10, 11.

#### PIN DESCRIPTION

#### A<sub>0</sub> - A<sub>9</sub> Address inputs

The address input lines select the memory location from which to read or write.

#### CS Chip Select (input, Active LOW)

The CS line selects the memory device for active operation.

WE Write Enable (Input, Active LOW)
When both CS and WE are LOW, data on the input lines is written to the location presented on the address input lines.

#### I/O<sub>1</sub> - I/O<sub>4</sub> Data In/Out Bus (Bidirectional)

These lines provide the path for data to be written to or read from the selected memory location.

V<sub>CC</sub> Power Supply

V<sub>SS</sub> Ground

TABLE 1. SUPPLY CURRENT ADVANTAGE

		Worst Case Current (mA at 0°C)				
Configuration	Part	100%	50%			
	Number	Duty Cycle	Duty Cycle			
2K x 8	9114	280	280			
	91L14	200	200			
4K x 12	9114	840	840			
	91L14	600	600			
8K x 16	9114	2240	2240			
	91L14	1600	1600			

### ABSOLUTE MAXIMUM RATINGS (Note 1)

Storage Temperature	65 to +150°C
Ambient Temperature with	55 to +125°C
Supply Voltage	0.5 V to +7.0 V
Signal Voltages with	0.5 V to +7.0 V
Power Dissipation	1.0 W
DC Output Current	10 MA

The products described by this specification include internal circuitry designed to protect input devices from damaging accumulations of static charge. It is suggested nevertheless, that conventional precautions be observed during storage, handling and use in order to avoid exposure to excessive voltages.

#### **OPERATING RANGES** (Note 2)

Commercial (C) Devices Ambient Temperature Supply Voltage (VCC)	(T <sub>A</sub> )0°C to +70°C +4.5V to +5.5 V
Military (M) Devices*  Case Temperature (To	)55°C to +125°C +4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

\*Military products 100% tested at T<sub>C</sub> = + 25°C, + 125°C and -55°C.

## DC CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 1, 2, 3 are tested unless otherwise noted)

Description		Test Conditions	Min.	Max.	Unit	
Output HIGH Current	V <sub>CC</sub> = + 4.5V V <sub>OH</sub> = 2.4V	91(L)14		-1.0		
		TA = 70°C	91(L)14	3.2		mA
Output LOW Current	V <sub>OL</sub> = 0.4V	TA = + 125°C	91(L)14	2.4		
Incid HIGH Voltage				2.0	Vcc	v
			-0.5	0.8		
	Vec ≤ VIN ≤ VCC			10		
Input Load Current		T <sub>A</sub> = 0 to +70°C T <sub>A</sub> = -55 to +125°C		-10	10	μΑ
Output Leakage Current	Output Disabled			-50	50	
	<del>-  </del>				75	m/
Output Short Circuit Current	(Note 3)				75	l
		Standard dev			70	
Operating Supply Current	Voc = Max	TA = 0°C	L devices	T	50	] m
	CS < VIL	T <sub>A</sub> = -55°C	T <sub>A</sub> = -55°C Standard devices L devices		60 60	
Innut Canacitance		f = 1.0 MHz,			7	p
	(Note 7)	TA = 25°C,			7	"י ר
	Output LOW Current Input HIGH Voltage Input LOW Voltage Input Load Current Output Leakage Current Output Short Circuit Current	Output LOW Current  Input HIGH Voltage Input LOW Voltage Input Load Current  Output Leakage Current  Output Short Circuit Current  Operating Supply Current  Input Capacitance  Vol. = 0.4V  Vss < VIN < Vcc Output Disabled  Vss < Vol < Vcc Output Disabled  Vcc = Max. CS < VIL	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

Notes: 1. Absolute Maximum Ratings are intended for user guidelines and are not tested.

2. For test and correlation purposes, ambient temperature is defined as the "instant-ON" case temperature.

2. For test purposes, not more than one output at a time should be shorted. Short-circuit test duration should not exceed 30 seconds. Actual

3. For test purposes, not more man one output at a time should be shorted. Shorted test bullation should be called testing is performed for only 5 ms.

1. Test conditions assume signal transition time of 10 ns or less, timing reference levels of 1.5 V, output loading of the specified I<sub>CL</sub>/I<sub>OH</sub> plus 100 pF or plus 5 pF for TCX. ToTP and TOTW.

The internel write time of the memory is defined by the overlap of CS LOW and WE LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input setup and hold timing should be referenced to the rising edge of the signal left that the internet are the signal within

6. The specified address access time will be valid only when Chip Select is low soon enough for too to elapse.

7. These parameters are not 100% tested, but are evaluated at initial characterization and at any time the design is modified where these Transition is measured from 1.5 V on the input to (V<sub>OH</sub> - 500 mV) and (V<sub>OL</sub> + 500 mV) on the output.

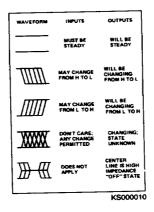
# **SWITCHING CHARACTERISTICS** over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted) (Notes 4-6)

		B Devices C Devices			vices	E Devices			
No.	Parameter Symbol	Parameter Description	Min.	Max.	Min.	Max.	Min.	Max.	Unit
R	EAD CYCLE								
1	tRC	Address Valid to Address Do Not Care Time (Read Cycle Time)	450		300		200		ns
2	tA	Address Valid to Data Out Valid Delay (Address Access Time)		450		300		200	ns
3	tco	Chip Select LOW to Data Out Valid (Note 6)		120		100		70	ns
4	tcx	Chip Select LOW to Data Out On (Notes 7, 8)	10		10		10		ns
5	<b>₽</b> OTD	Chip Select HIGH to Data Out Off (Notes 7, 8)		100		80		60	CS
6	<sup>‡</sup> OHA	Output hold after address change	50		50		50		ns
W	RITE CYCLE								
7	twc	Address Valid to Address Do Not Care Time (Write Cycle Time)	450		300		200		ns
8	₩	Write Enable LOW to Write Enable HIGH Time (Note 5)	200		150		120		ns
9	twn	Write Enable HIGH to Address Do Not Care Time	0		0		0	-	ns
10	torw	Write Enable LOW to Data Out Off Delay (Notes 7, 8)		100		80		60	ns
11	tow	Data In Valid to Write Enable HIGH Time	200		150		120		ns
12	t <sub>DH</sub>	Write Enable HIGH to Data In Do Not Care Time	0		0		0		ns
13	taw	Address Valid to Write Enable LOW Time	0		0		0		ns
14	tcw	Chip Select LOW to Write Enable HIGH Time (Note 5)	200		150		120		90

Notes: See notes following DC Characteristics table.

# SWITCHING WAVEFORMS

### KEY TO SWITCHING WAVEFORMS

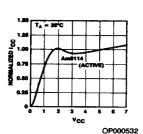


Notes: See notes following DC Characteristics table.

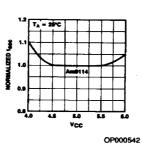
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#### TYPICAL PERFORMANCE CURVES

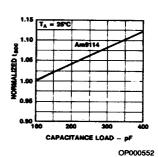
#### Normalized Supply Current Versus Supply Voltage



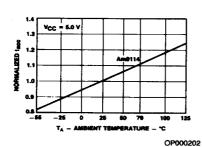
Normalized Access Time Versus Supply Voltage



Normalized Access Time Versus Output Loading



Normalized Access Time Versus Ambient Temperature



Normalized Supply Current Versus Ambient Temperature

